



ALPHA & OMEGA
SEMICONDUCTOR

AON3818

24V Dual N-Channel α MOS™

General Description

- Trench Power α MOS™ LV technology
- Low $R_{DS(ON)}$
- Low Gate Charge
- ESD protection
- RoHS and Halogen-Free Compliant

Applications

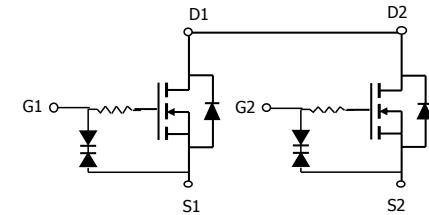
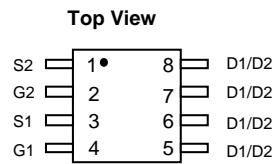
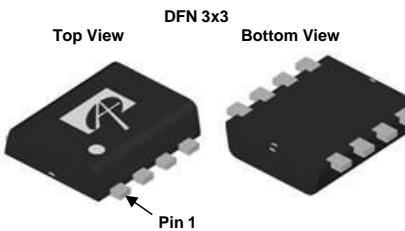
- Battery protection switch
- Mobile device battery charging and discharging

Product Summary

V_{DS}	24V
I_D (at $V_{GS}=4.5V$)	8A
$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 13.5mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.0V$)	< 14mΩ
$R_{DS(ON)}$ (at $V_{GS}=3.7V$)	< 15mΩ
$R_{DS(ON)}$ (at $V_{GS}=3.1V$)	< 17mΩ
$R_{DS(ON)}$ (at $V_{GS}=2.5V$)	< 21mΩ

Typical ESD protection

HBM Class 2



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AON3818	DFN 3x3	Tape & Reel	3000

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum		Units
Drain-Source Voltage	V_{DS}	24		V
Gate-Source Voltage	V_{GS}	± 12		V
Continuous Drain Current ^G	I_D	8	A	
$T_A=70^\circ\text{C}$		6		
Pulsed Drain Current ^C	I_{DM}	32	W	
$T_A=25^\circ\text{C}$	P_D	2.7		
$T_A=70^\circ\text{C}$		1.7		
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	R_{0JA}	35	45	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		60	75	°C/W
Maximum Junction-to-Lead	R_{0JL}	15	20	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	24			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 10\text{V}$			± 10	μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.4	0.8	1.2	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=8\text{A}$ $T_J=125^\circ\text{C}$	7.5	10.8	13.5	$\text{m}\Omega$
		$V_{GS}=4.0\text{V}, I_D=6\text{A}$	10.5	15	19	
		$V_{GS}=3.7\text{V}, I_D=6\text{A}$	7.8	11.2	14	
		$V_{GS}=3.1\text{V}, I_D=4\text{A}$	8	11.5	15	
		$V_{GS}=2.5\text{V}, I_D=4\text{A}$	8	12.5	17	
		$V_{GS}=2.5\text{V}, I_D=4\text{A}$	8.6	14.8	21	
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=8\text{A}$		42		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.66	1	V
I_S	Maximum Body-Diode Continuous Current				4	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=12\text{V}, f=1\text{MHz}$		840		pF
C_{oss}	Output Capacitance			210		pF
C_{rss}	Reverse Transfer Capacitance			205		pF
R_g	Gate resistance	f=1MHz		2		k Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=12\text{V}, I_D=8\text{A}$		9.5	15	nC
Q_{gs}	Gate Source Charge			1.5		nC
Q_{gd}	Gate Drain Charge			4.5		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=4.5\text{V}, V_{DS}=12\text{V}, R_L=1.5\Omega, R_{\text{GEN}}=3\Omega$		0.3		μs
t_r	Turn-On Rise Time			0.8		μs
$t_{D(\text{off})}$	Turn-Off DelayTime			1.7		μs
t_f	Turn-Off Fall Time			5.2		μs

A. The value of R_{iJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_0 is based on $T_{J(\text{MAX})}=150^\circ\text{ C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

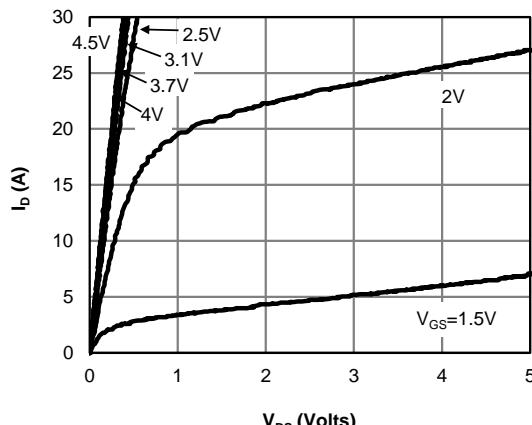
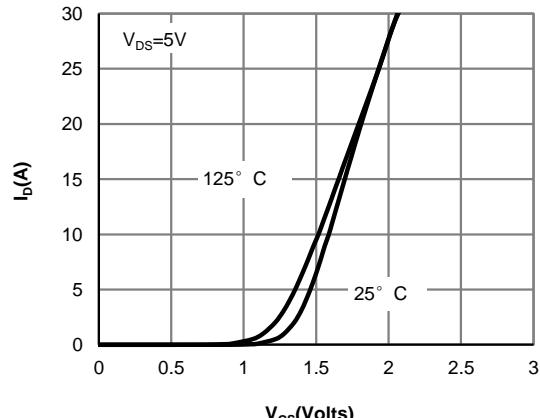
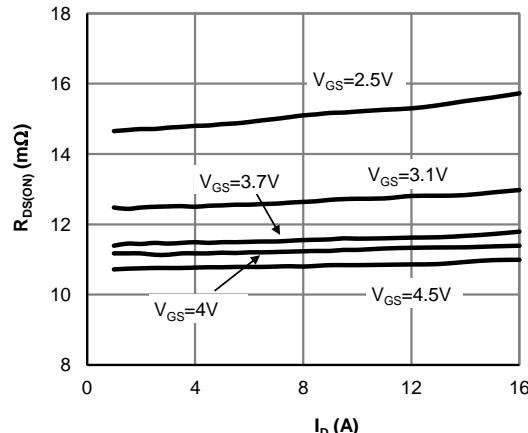
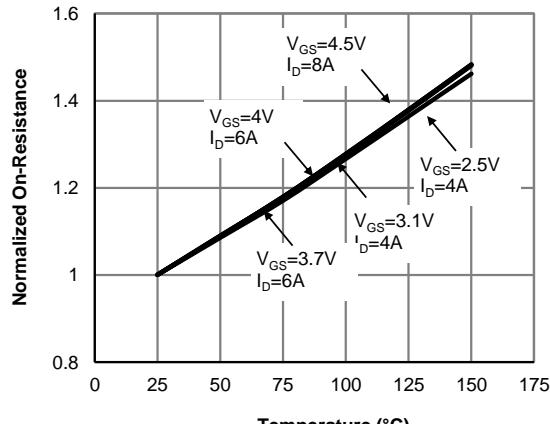
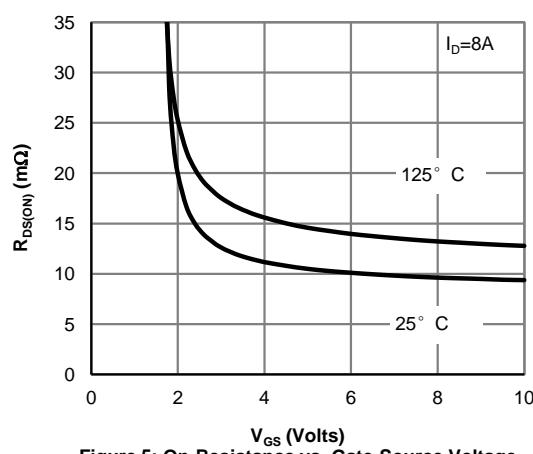
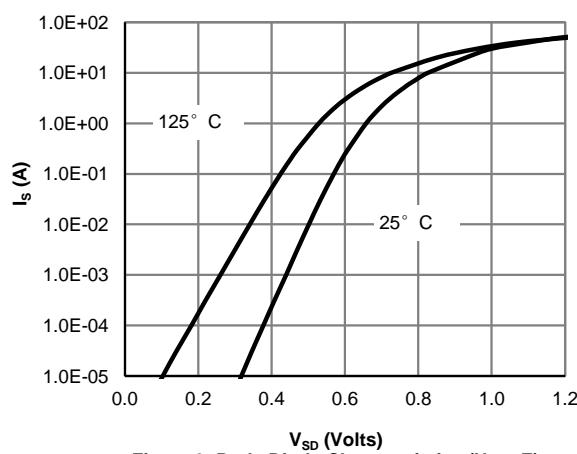
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{ C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{ C}$.

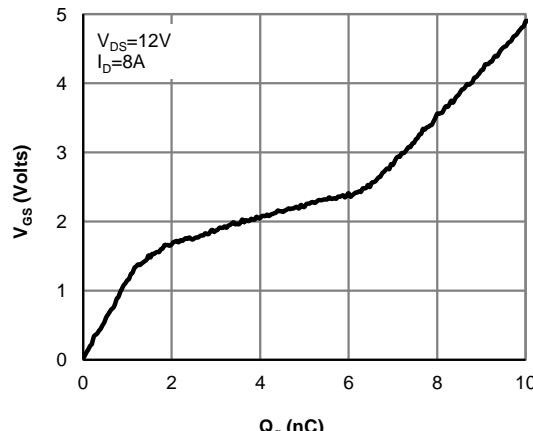
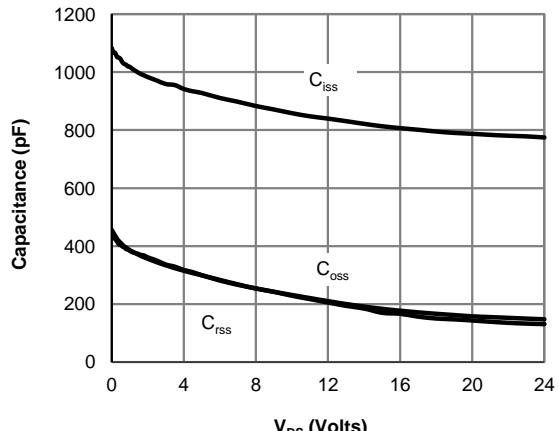
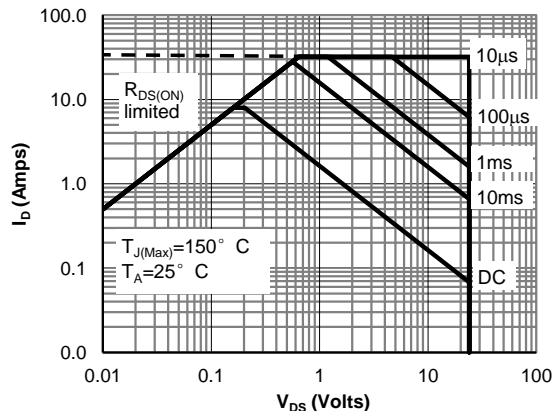
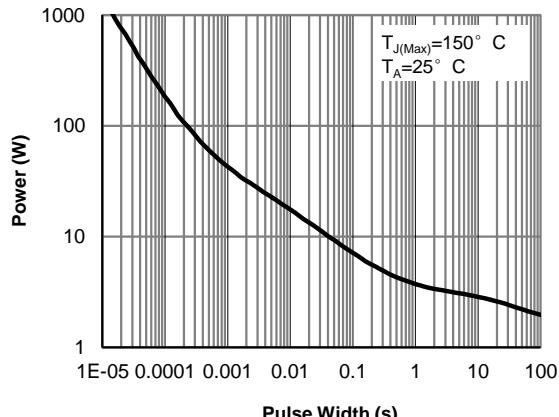
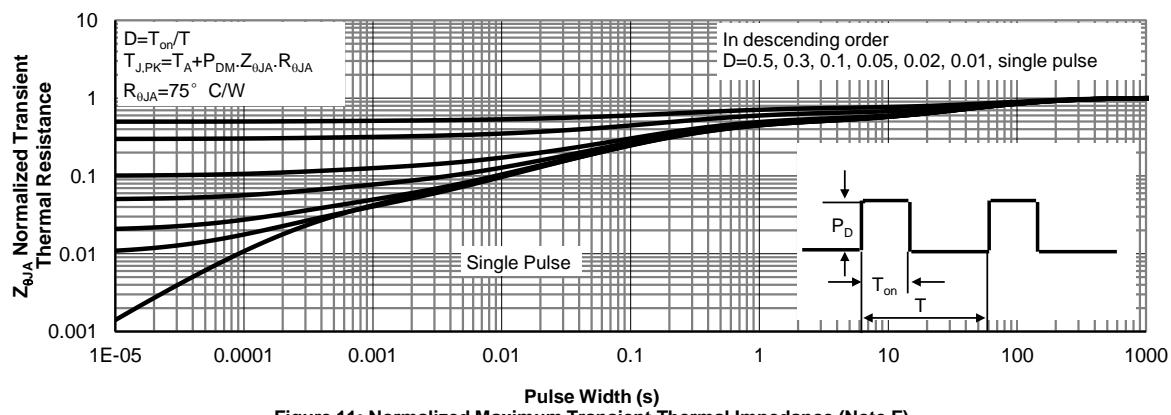
D. The R_{iJA} is the sum of the thermal impedance from junction to lead R_{iJL} and lead to ambient.

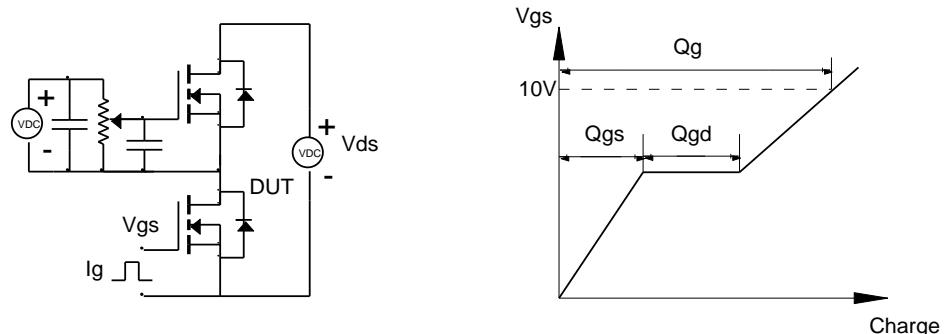
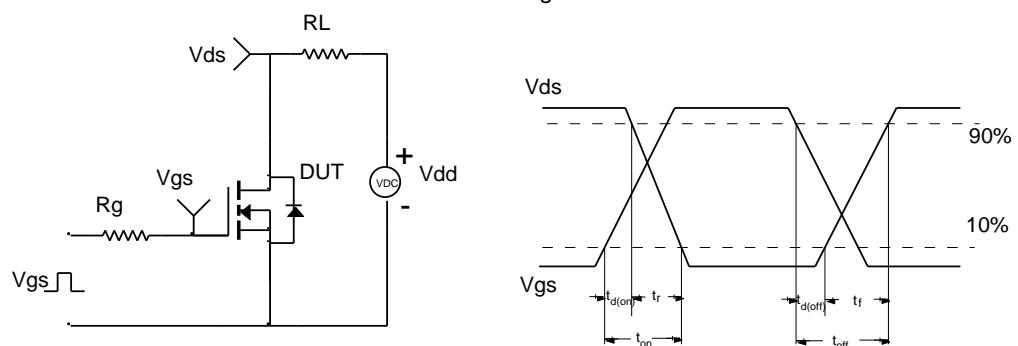
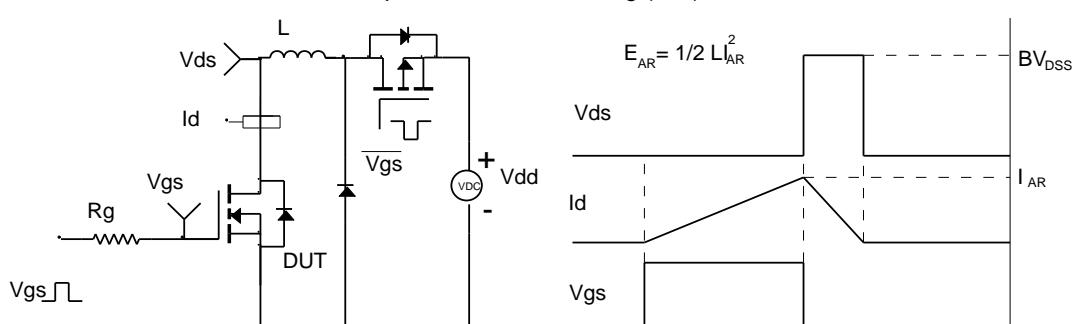
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{ C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
